

Notice of References Cited

Application/Control No.

10/086,886

Applicant(s)/Patent Under
Reexamination
BANNO ET AL.

Examiner

Dah-Wei D. Yuan

Art Unit

1745

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6190805	02-2001	Takeuchi et al.	429/307
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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